



# 제 29회 한국반도체학술대회

The 29th Korean Conference on Semiconductors

2022년 1월 24일(월)~ 26일(수) | 강원도 하이원 그랜드호텔(컨벤션타워)

2022년 1월 25일(화), 09:00-10:30

Room F (스페이드 I, 6층)

## G. Device & Process Modeling, Simulation and Reliability 분과

### [TF1-G] Thin Film Devices

좌장: 장지원 교수(연세대학교), 우지용 교수(경북대학교)

<p><b>TF1-G-1</b> 09:00-09:15</p>	<p><b>Photonic Capacitance-Voltage Technique with Empirical Distributed Capacitance Model for Characterization of Traps in AOS TFTs</b>          Ji Hee Ryu, Han Bin Yoo, Haesung Kim, Ju Young Park, Jong-Ho Bae, Sung-Jin Choi, Dae Hwan Kim, and Dong Myong Kim  <i>School of Electrical Engineering, Kookmin University</i></p>
<p><b>TF1-G-2</b> 09:15-09:30</p>	<p><b>Comprehensive DC Technique for Extraction of Threshold Voltage, Parasitic Resistances, and Mobility Enhancement Parameter in AOS TFTs</b>          Ju Young Park, Haesung Kim, Han Bin Yoo, Ji Hee Ryu, Jong-Ho Bae, Sung-Jin Choi, Dae Hwan Kim, and Dong Myong Kim  <i>School of Electrical Engineering, Kookmin University</i></p>
<p><b>TF1-G-3</b> 09:30-09:45</p>	<p><b>Multiple Stretched-Exponential Function-Based Physical Model of a Local Threshold Voltage Shift in IGZO TFTs Under Current Stress for Instability-aware Circuit Design</b>          Tae Jun Yang, Je-Hyuk Kim, Hee Jun Lee, Sung-Jin Choi, Jong-Ho Bae, Dong Myong Kim, and Dae Hwan Kim  <i>School of Electrical Engineering, Kookmin University</i></p>
<p><b>TF1-G-4</b> 09:45-10:00</p>	<p><b>Correlation of the Lateral Profile of Carrier Concentration and <math>\Delta L</math> to <math>V_T</math>, and Its Dependence on Oxygen Content in IGZO TFTs</b>          Seung Joo Myoung, Chang Il Ryoo, Je-Hyuk Kim, Dong Myong Kim, Sung-Jin Choi, Jong-Ho Bae, and Dae Hwan Kim  <i>School of Electrical Engineering, Kookmin University</i></p>
<p><b>TF1-G-5</b> 10:00-10:15</p>	<p><b>Self-Heating-assisted Peroxide Generation as the Origin of Channel Width-dependent Instability of Amorphous InZnO TFTs under Current Stress</b>          Won Jung Kim, Jingyu Park, Sungju Choi, Youngjin Seo, Je-Hyuk Kim, Inseok Chae, Changil Ryoo, Dong Myong Kim, Sung-Jin Choi, Jong-Ho Bae, and Dae Hwan Kim  <i>School of Electrical Engineering, Kookmin University</i></p>
<p><b>TF1-G-6</b> 10:15-10:30</p>	<p><b>AC Analysis of Anisotropic In-Plane Carrier Transport in 2-Dimensional Layered Materials</b>          Hyunjin Ji<sup>1</sup>, Gwanmu Lee<sup>2</sup>, and Dongseok Suh<sup>2</sup>  <sup>1</sup>Department of Electrical Engineering, University of Ulsan, <sup>2</sup>Department of Energy Science, Sungkyunkwan University</p>